

QuickPRO[™] Products for Precision Metrology

High-Speed Surface Inspection for Precision Machining, PCBs, ASICs, & Optics (Spherical, Aspheric, Diffractive, Microlens, Injection-Molded, Thin-Film)

OATi's QuickPRO[™] metrology systems utilize up to two opposing chromatic confocal optical sensors to provide non-contact z-axis measurement accuracies below 50-nm, and spatial data sampling down to 2-µm. In addition, for the most sensitive applications in surface metrology, we also offer an interferometric version (QuickPRO[™] OCT) for hypersensitive (<5-nm) applications.

Our single-sensor platforms (QuickPRO[™] RPS and QuickPRO[™] 3D) provide you with a simple, reliable, strategic baseline for high-accuracy surface metrology, while our dual-sensor platforms (QuickPRO[™] CUBE-Mini and QuickPRO[™] CUBE-100) allow dual-surface characterization without requiring movement of the unit-under-test—the advantage being the added ability to measure wedge and surface decentration.

Features

- Compact, bench-top units with integrated enclosures and vibration-isolated operation
- Nanometer precision linear motor stages for customized scanning routines covering up to 150-mm (200-mm scanning capability in development)
- Al/robotics-compatible control software to enable full automation capability
- Point-cloud analysis routines for identification of surface variations with hypersensitive data visualization
- High dynamic range detection routines for characterizing surfaces of up to 45-deg from normal





Top/Bottom

Top (Zoomed)

New and Improved

Diffractive Aspheres

- Measure surface deviations in zone diameter, depth, and transition gap.
 Identify localized
- slope errors.



Aspheric Surfaces

- Measure tip/tilt of lens
- Verify P-V and SAG
- Identify deviation from
 the specified lens

Micro-Lens Arrays

 Inspect single point diamond turned (SPDT) mold geometry as pre-production QA



• Identify local punctures or other structural aberrations made by the forming process





PCB Substrates

- Inspect line width and feature spacing
- Scan for warpage
 Measure via size, depth and position

Transparent Film

- Measure top and bottom surfaces of transparent films to identify any critical
- deviations in thickness
 Use generated plot to pinpoint and implement process improvements to eliminate potential failure zones





QuickPRO[™] Products



	QuickPRO-CUBE	QuickPRO-RPS	QuickPRO-3D	QuickPRO-OCT
Profilometry	Dual Surface	Single Surface Rotary Scan	Single Surface	Thickness Mapping
Scan Range	50 x 50 x 35 mm 100 x 100 x 50 mm	Ø150 mm x 50 mm	100 x 100 x 50 mm	100 x 100 x 50 mm
Technology	Chromatic Confocal Point Sensor	Chromatic Confocal Point Sensor	Chromatic Confocal Point or Line Sensor	Low-Coherence Interferometry
Resolution	 Lateral ≤ 2µm Axial ≤ 50nm 	 Lateral ≤ 2µm Axial ≤ 50nm 	 Lateral ≤ 2µm Axial ≤ 50nm 	 Lateral ≤ 5µm Axial ≤ 5nm
Accuracy	• XYZ < 1µm	• XYZ < 1µm	• XYZ < 1µm	• XY < 1µm; Z < 0.1µm
Measurands	 ROC/Thickness Decenter/Wedge	Surface profileAlignment to datums	Surface profile	 Thickness and profile of thick films (>1µm) Wafer bow/warp

Chromatic Confocal Microscopy

- Extensive chromatic aberration maps color to distance through spectroscopy.
- Spectral peak measurement provides extensive dynamic range for variations in surface reflectivity.
- High (>4kHz) sample rate for spatial metrology.





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